

Search Notes

Application/Control No.

10/730,322

Examiner

Shih-Chao Chen

Applicant(s)/Patent under
Reexamination

KATOH ET AL.

Art Unit

2821

SEARCHED

Class	Subclass	Date	Examiner
343	702, 700MS, 846	6/27/2005	CHEN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR